

CG65030TBD



Description

CG65030TBD is a 650V GaN-on-Si enhancement-mode power transistor in TO-Leaded top-side cooling (TOLT) package. The properties of GaN allow for high current, high breakdown voltage and high switching frequency. The TOLT package offers superior heat dissipation, low parasitic resistance/inductance and high solderability, which can fully release device potential and make GaN better apply to industrial applications.

Features

- 650V GaN enhancement-mode power switch
- $R_{DS(on)}$, max 30mΩ
- Recommended gate drive voltage 0V ~ 6V
- Ultra-low FOM
- Ultra-high switching frequency
- Reverse current capability
- Zero reverse recovery loss
- Monolithic integrated ESD protection, HBM class 2, CDM class C3
- RoHS, Pb-free, REACH-compliant

Applications

- AC-DC converters, DC-DC converters
- Bridgeless totem pole PFC, data center, telecom, network SMPS
- Uninterruptable power supplies (UPS)
- Solar inverters, energy storage systems
- On board charger (OBC)
- Charging pile
- Traction inverter
- Industrial motor drives

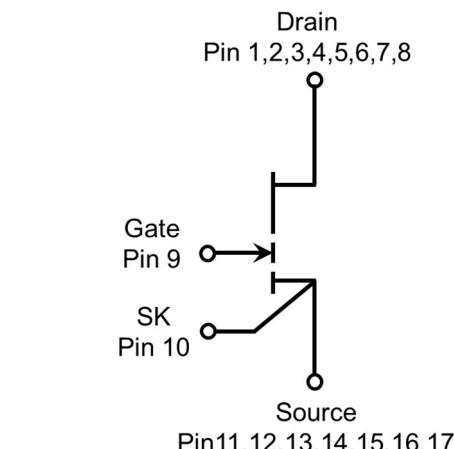
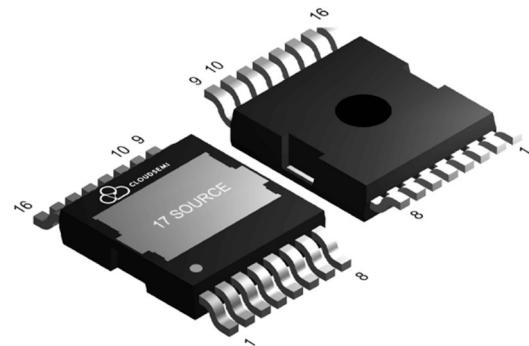


Table 1 Key Performance Parameters at $T_j = 25^\circ\text{C}$

Parameters	Values	Units
V_{DS} , max	650	V
$R_{DS(on)}$, max	30	mΩ
Q_G , typ	14.3	nC
I_D , Pulse	120	A
Q_{oss} @ 400 V	133	nC
Q_{rr}	0	nC

Table 2 Ordering Information

Ordering Code	Package	Marking	Packing
CG65030TBD	TOLT	CG65030TBD	Reel

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1 Maximum ratings

at $T_j = 25^\circ\text{C}$ unless otherwise specified. Continuous application of maximum ratings can deteriorate transistor lifetime. For further information, contact CloudSemi sales office.

Table 3 Maximum ratings

Parameters	Sym.	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Drain-source voltage	$V_{DS, \text{max}}$	-	-	650	V	$V_{GS} = 0 \text{ V}$, $I_D = 10 \mu\text{A}$
Drain-source voltage transient ¹	$V_{DS, \text{transient}}$	-	-	850	V	$V_{GS} = 0 \text{ V}$, $V_{DS} = 850 \text{ V}$
Continuous current, drain-source	I_D	-	-	60	A	$T_c = 25^\circ\text{C}$
Pulsed current, drain-source ²	$I_{D, \text{pulse}}$	-	-	120	A	$T_c = 25^\circ\text{C}$; $V_G = 6 \text{ V}$
Pulsed current, drain-source ²	$I_{D, \text{pulse}}$	-	-	50	A	$T_c = 150^\circ\text{C}$; $V_G = 6 \text{ V}$
Gate-source voltage, continuous ³	V_{GS}	-7	-	+7	V	$T_j = -55^\circ\text{C}$ to 150°C
Gate-source voltage, pulsed	$V_{GS, \text{pulse}}$	-20	-	+10	V	$T_j = -55^\circ\text{C}$ to 150°C ; $t_{\text{pulse}} = 50 \text{ ns}$, $f = 100 \text{ kHz}$; open drain
Power dissipation	P_{tot}	-	-	272	W	$T_c = 25^\circ\text{C}$
Operating temperature	T_j	-55	-	+150	$^\circ\text{C}$	
Storage temperature	T_{stg}	-55	-	+150	$^\circ\text{C}$	

1. $V_{DS, \text{transient}}$ is intended for surge rating during non-repetitive events, $t_{\text{pulse}} < 1 \mu\text{s}$.

2. Pulse width = 10 μs .

3. The minimum V_{GS} is clamped by ESD protection circuit, as shown in Figure 8.

2 Thermal characteristics

Table 4 Thermal characteristics

Parameters	Symbols	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Thermal resistance, junction-case	R_{thJC}	-	-	0.46	$^\circ\text{C/W}$	
Thermal resistance, junction-ambient	R_{thJA}	-	-	30	$^\circ\text{C/W}$	
Reflow soldering temperature	T_{sold}	-	-	260	$^\circ\text{C}$	MSL3

1. Device mounted on 1.6 mm PCB thickness FR4, 4-layer PCB with 2 oz copper on each layer. The recommendation for thermal vias under the thermal pad is 0.3 mm diameter (12mil) with 0.889 mm pitch (35mil). The copper layers under the thermal pad and drain pad are 25 x 25 mm^2 each. The PCB is mounted in horizontal position without air stream cooling.

3 Electrical characteristics

at $T_j = 25^\circ\text{C}$, unless otherwise specified.

Table 5 Static characteristics

Parameters	Sym.	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Gate threshold voltage	$V_{GS(TH)}$	1.1	1.7	2.6	V	$I_D = 15 \text{ mA}; V_{DS} = V_{GS}; T_j = 25^\circ\text{C}$
		-	1.9	-		$I_D = 15 \text{ mA}; V_{DS} = V_{GS}; T_j = 150^\circ\text{C}$
Drain-source leakage current	I_{DSS}	-	2	50	μA	$V_{DS} = 650 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25^\circ\text{C}$
		-	35	-		$V_{DS} = 650 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150^\circ\text{C}$
Gate-source leakage current	I_{GSS}	-	150	-	μA	$V_{GS} = 6 \text{ V}; V_{DS} = 0 \text{ V}$
Reverse Gate leakage current	I_{RGL}	-	-15	-	nA	$V_{GS} = -6 \text{ V}; V_{DS} = 0 \text{ V}$
Drain-source on-state resistance	$R_{DS(on)}$	-	25	30	$\text{m}\Omega$	$V_{GS} = 6 \text{ V}; I_D = 20 \text{ A}; T_j = 25^\circ\text{C}$
		-	55	-	$\text{m}\Omega$	$V_{GS} = 6 \text{ V}; I_D = 20 \text{ A}; T_j = 150^\circ\text{C}$
Gate resistance	R_G	-	1.0	-	Ω	$f = 5 \text{ MHz}; \text{open drain}$

Table 6 Dynamic characteristics

Parameters	Sym.	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Input capacitance	C_{iss}	-	500	-	pF	$V_{GS} = 0 \text{ V}; V_{DS} = 400 \text{ V}; f = 1 \text{ MHz}$
Output capacitance	C_{oss}	-	129	-	pF	$V_{GS} = 0 \text{ V}; V_{DS} = 400 \text{ V}; f = 1 \text{ MHz}$
Reverse transfer capacitance	C_{rss}	-	0.94	-	pF	$V_{GS} = 0 \text{ V}; V_{DS} = 400 \text{ V}; f = 1 \text{ MHz}$
Effective output capacitance, energy related ¹	$C_{o(er)}$	-	228	-	pF	$V_{GS} = 0 \text{ V}; V_{DS} = 0 \text{ to } 400 \text{ V}$
Effective output capacitance, time related ²	$C_{o(tr)}$	-	334	-	pF	$V_{GS} = 0 \text{ V}; V_{DS} = 0 \text{ to } 400 \text{ V}$
Output charge	Q_{oss}	-	133	-	nC	
Output Capacitance Stored Energy	E_{oss}	-	18	-	μJ	$V_{GS} = 0 \text{ V}; V_{DS} = 400 \text{ V}; f = 1 \text{ MHz}$
Turn-on delay time	$t_{d(on)}$	-	4.7	-	ns	
Turn-off delay time	$t_{d(off)}$	-	13.5	-	ns	
Rise time	t_r	-	12	-	ns	
Fall time	t_f	-	18	-	ns	
Switching Energy during turn-on	E_{on}	-	134	-	μJ	$V_{DS} = 400 \text{ V}; I_D = 20 \text{ A}; L = 120 \mu\text{H};$ $V_{GS} = 6 \text{ V}; R_{on} = 10 \Omega; R_{off} = 1 \Omega$
Switching Energy during turn-off	E_{off}	-	17.5	-	μJ	

1. $C_{o(er)}$ is the fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400 V.

2. $C_{o(tr)}$ is the fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400 V.

Table 7 Gate charge characteristics

Parameters	Sym.	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Gate charge	Q _G	-	14.3	-	nC	V _{GS} = 0 to 6 V; V _{DS} = 400 V; I _D = 60 A
Gate-source charge	Q _{GS}	-	3.7	-	nC	
Gate-drain charge	Q _{GD}	-	3.7	-	nC	
Gate plateau voltage	V _{plat}	-	2.8	-	V	

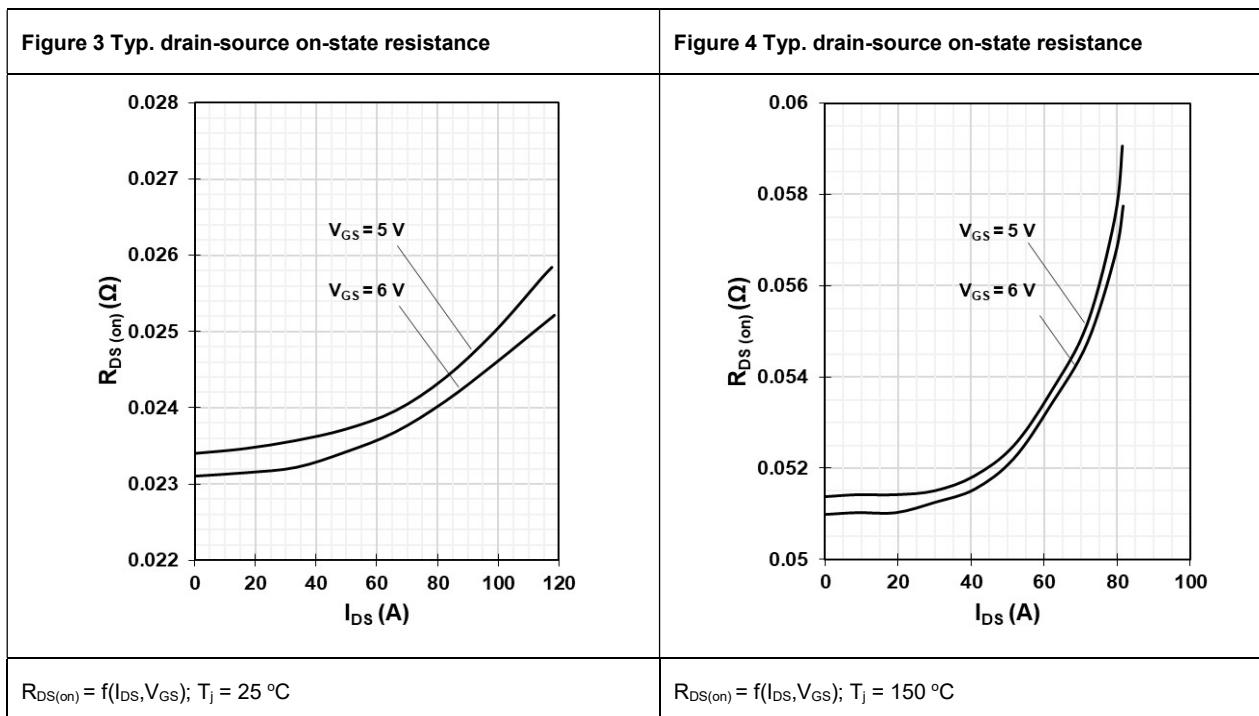
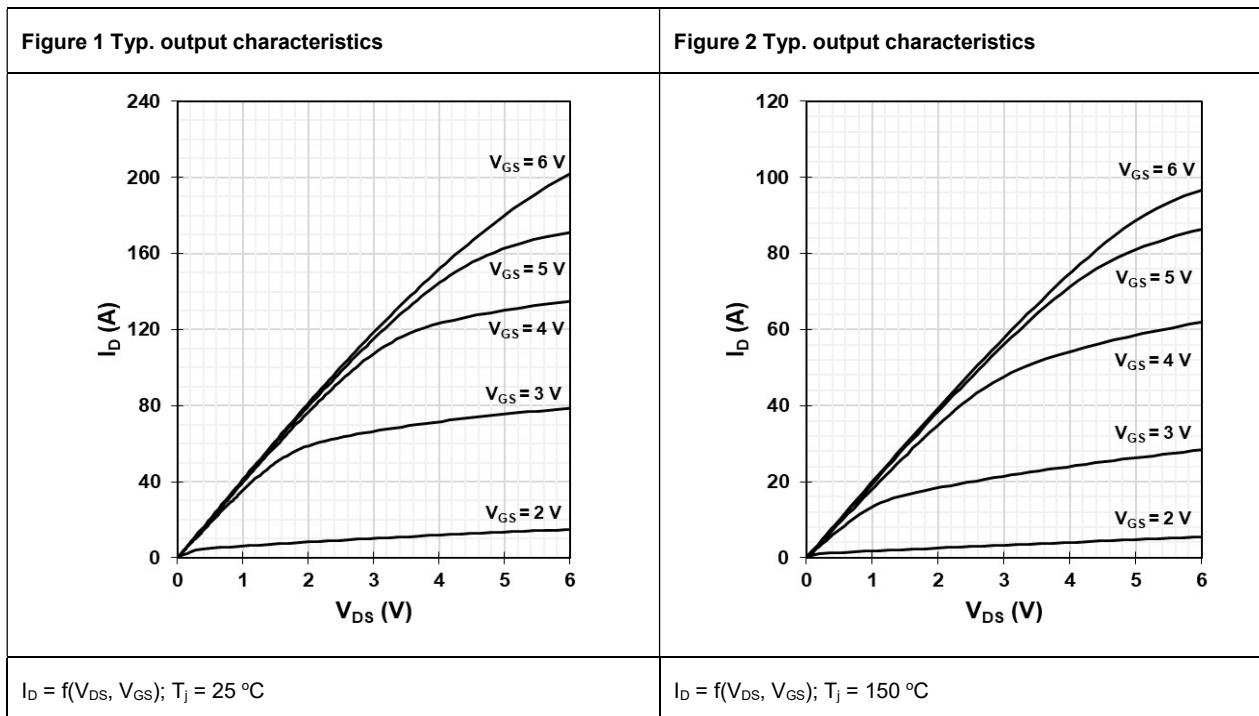
Table 8 Reverse conduction characteristics

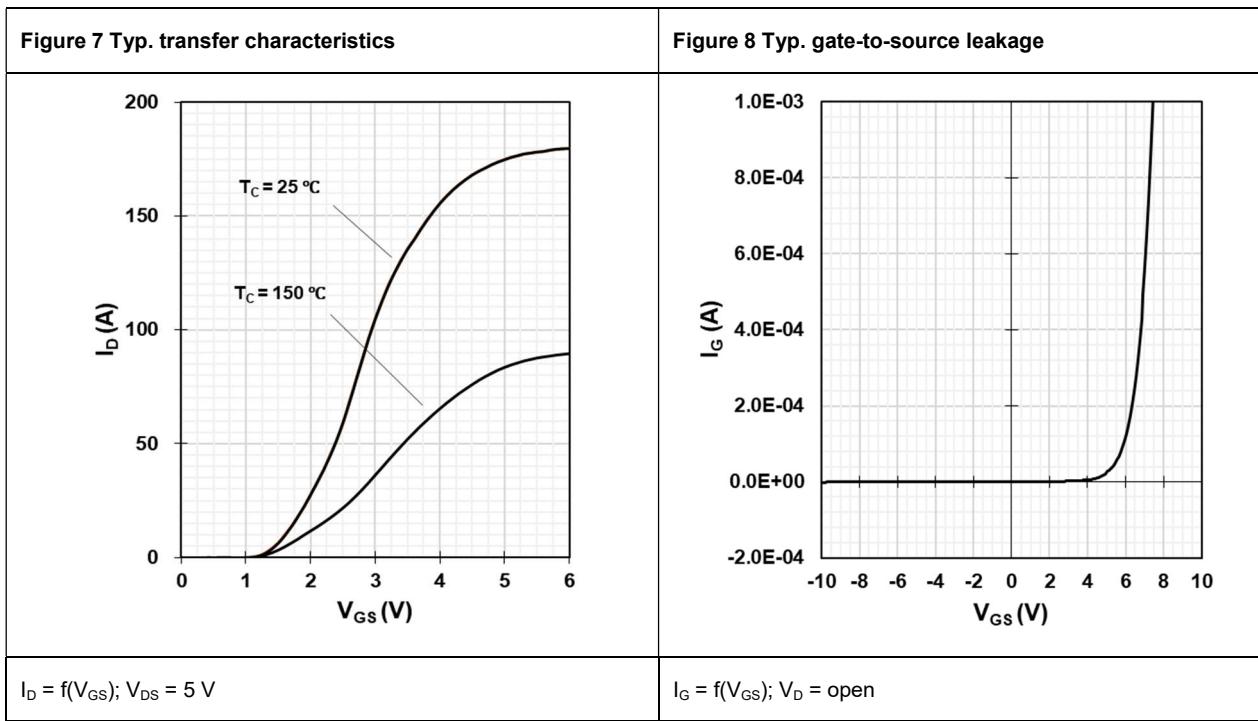
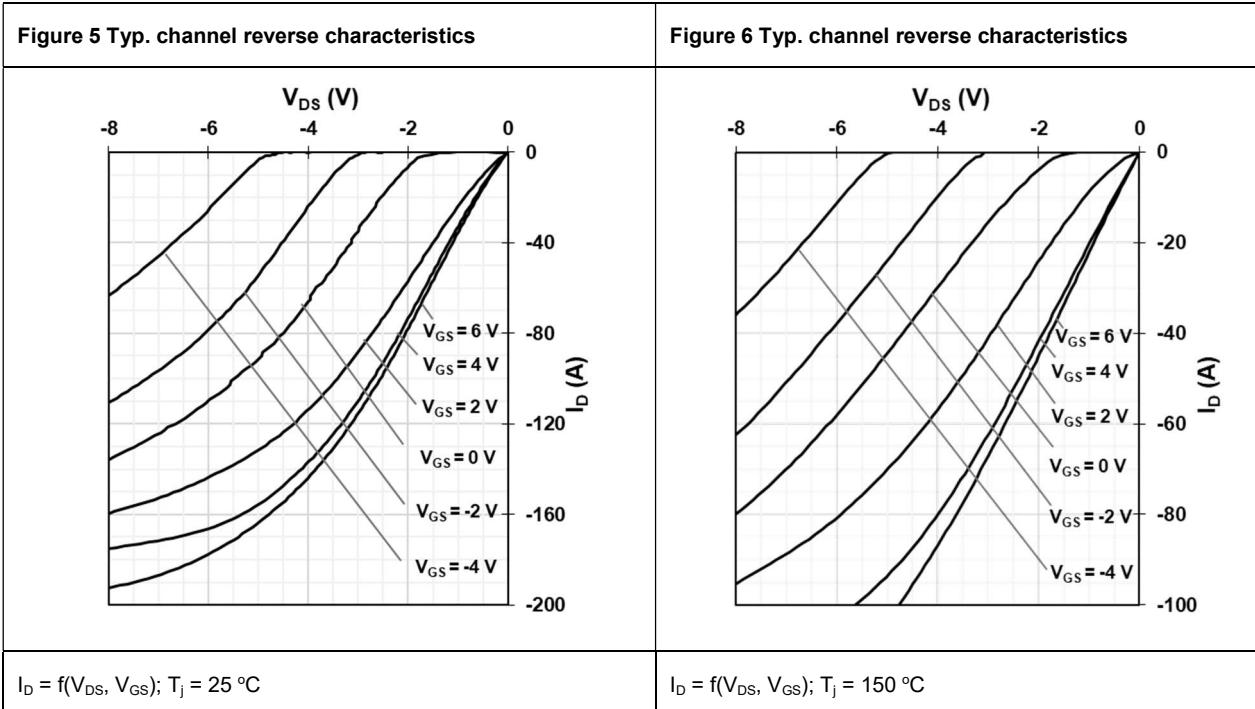
Parameters	Sym.	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Source-drain reverse voltage	V _{SD}	-	3.8	-	V	V _{GS} = 0 V; I _{SD} = 60 A
Pulsed current, reverse	I _S , pulse	-	80	-	A	V _{GS} = 6 V
Reverse recovery charge ¹	Q _{rr}	-	0	-	nC	I _{SD} = 60 A; V _{DS} = 400 V
Reverse recovery time	t _{rr}	-	0	-	ns	
Peak reverse recovery current	I _{rrm}	-	0	-	A	

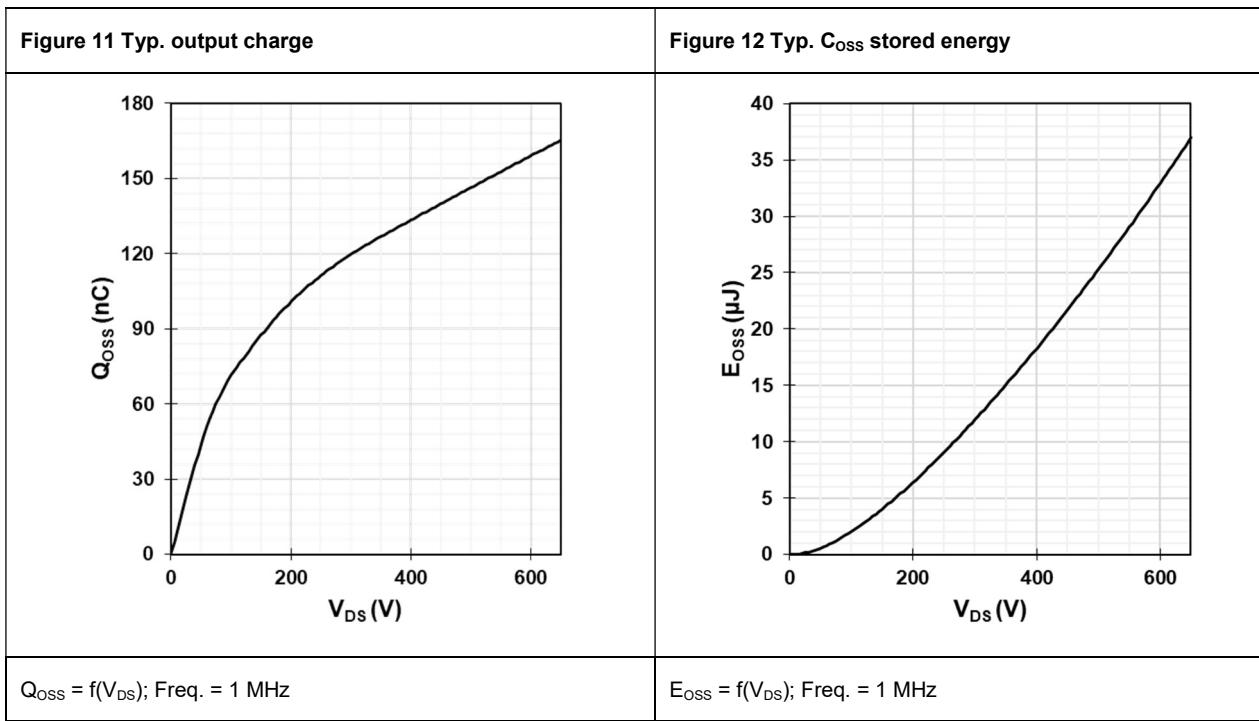
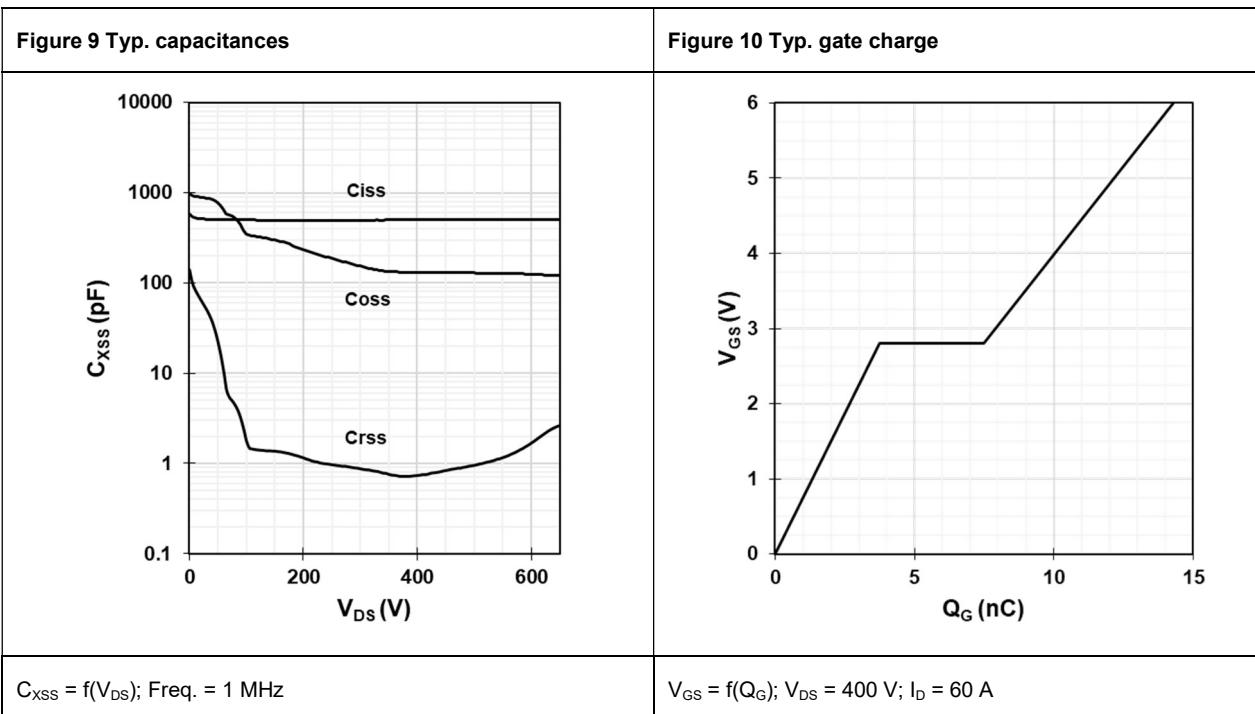
1. Excluding Q_{oss}

4 Electrical characteristics diagrams

at $T_j = 25^\circ\text{C}$, unless otherwise specified.







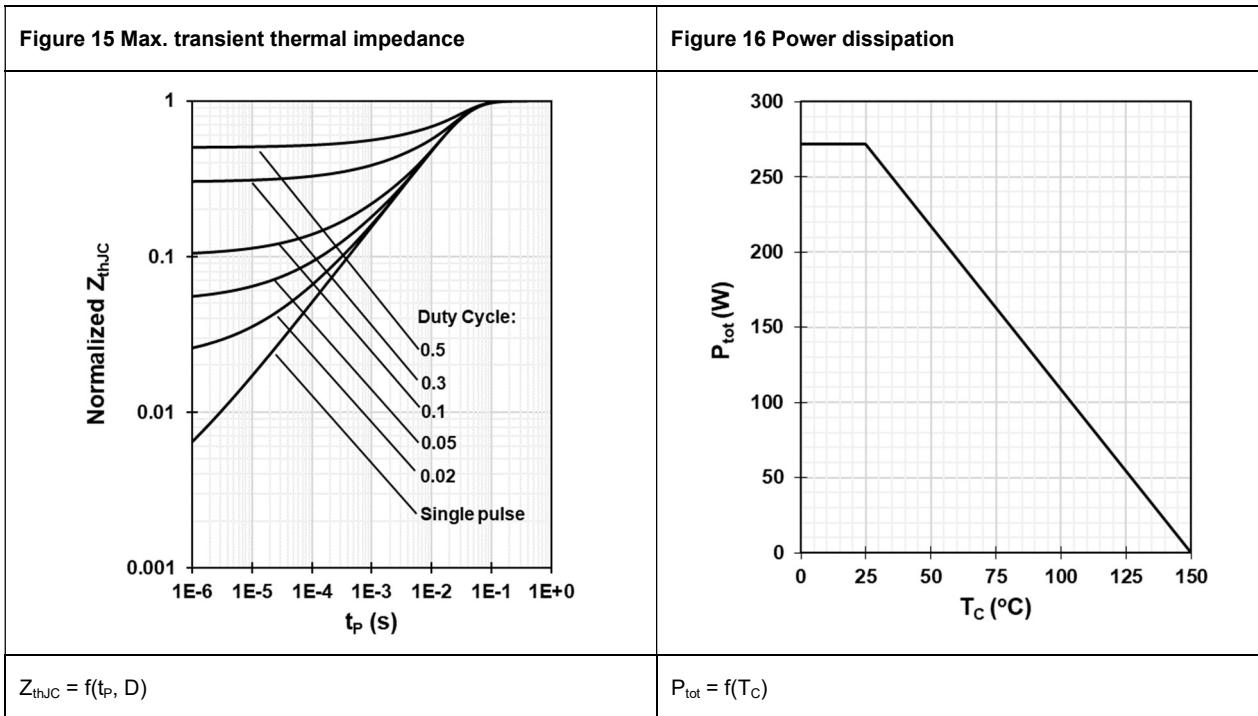
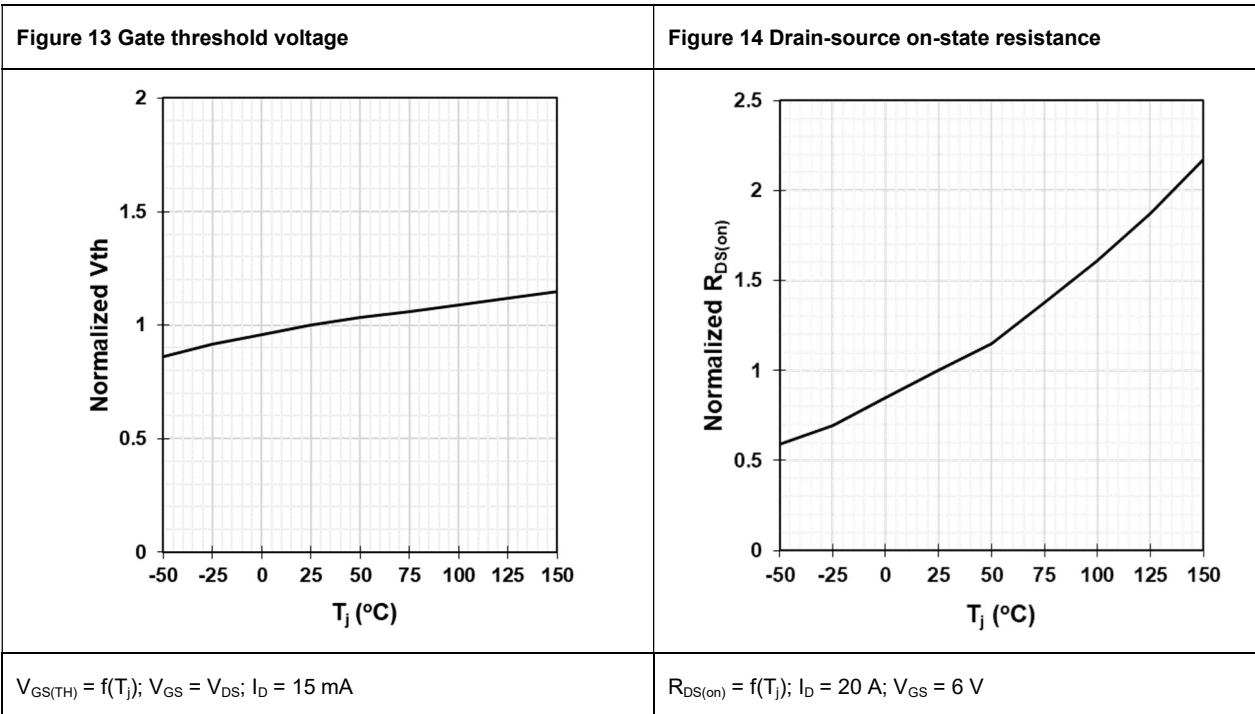


Figure 17 Safe operating area

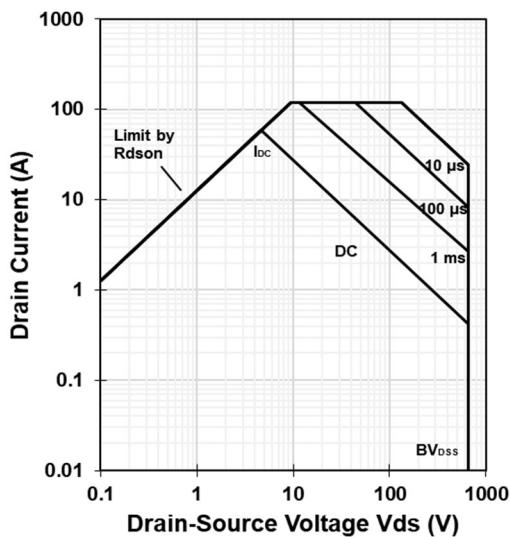
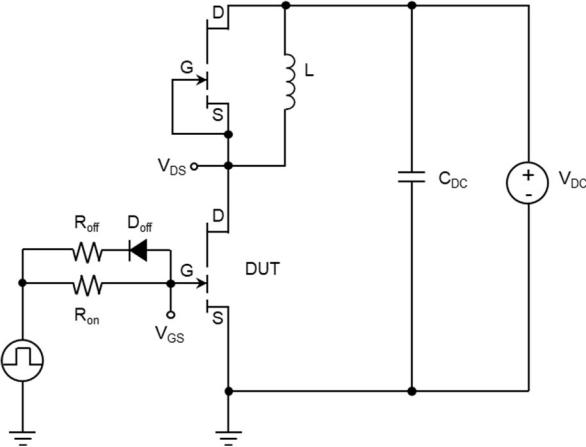


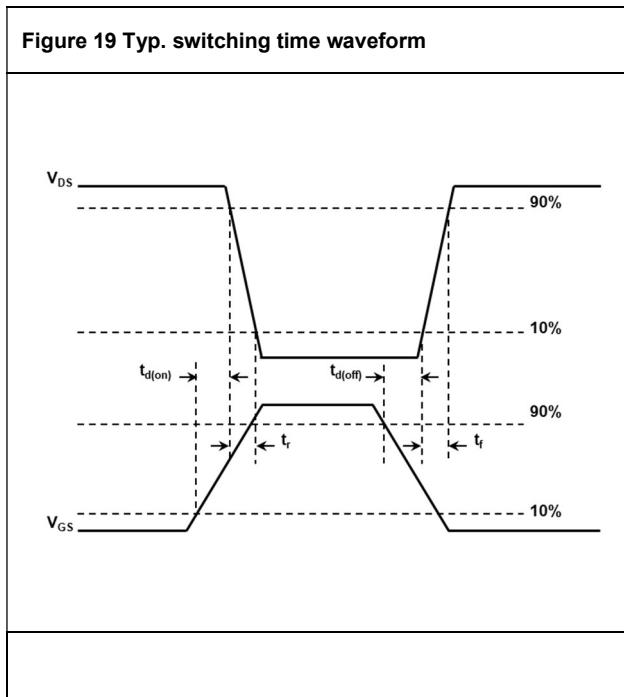
Figure 18 Switching time test circuit



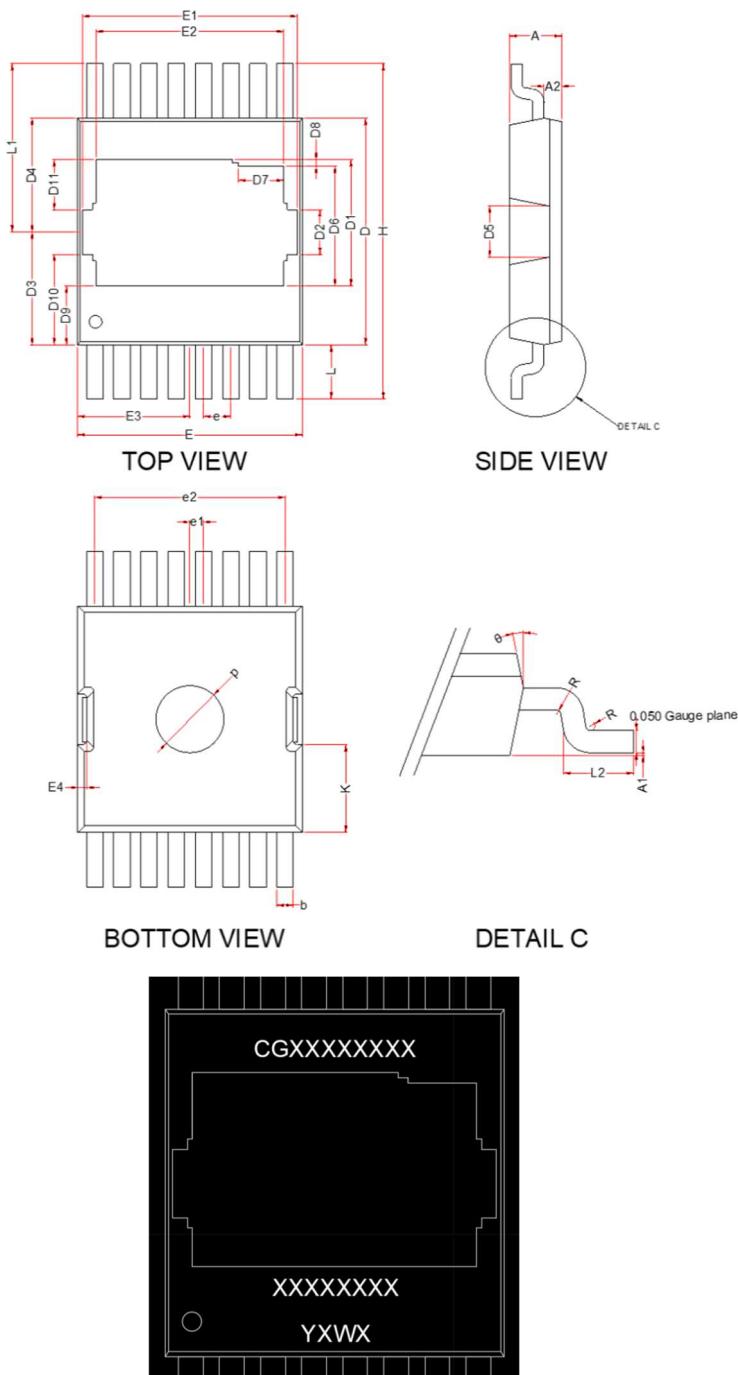
$I_D = f(V_{DS})$; $T_C = 25^\circ\text{C}$

$V_{DS} = 400 \text{ V}$, $I_D = 20 \text{ A}$, $L = 120 \mu\text{H}$, $V_{GS} = 6 \text{ V}$,
 $R_{on} = 10 \Omega$, $R_{off} = 1 \Omega$

Figure 19 Typ. switching time waveform



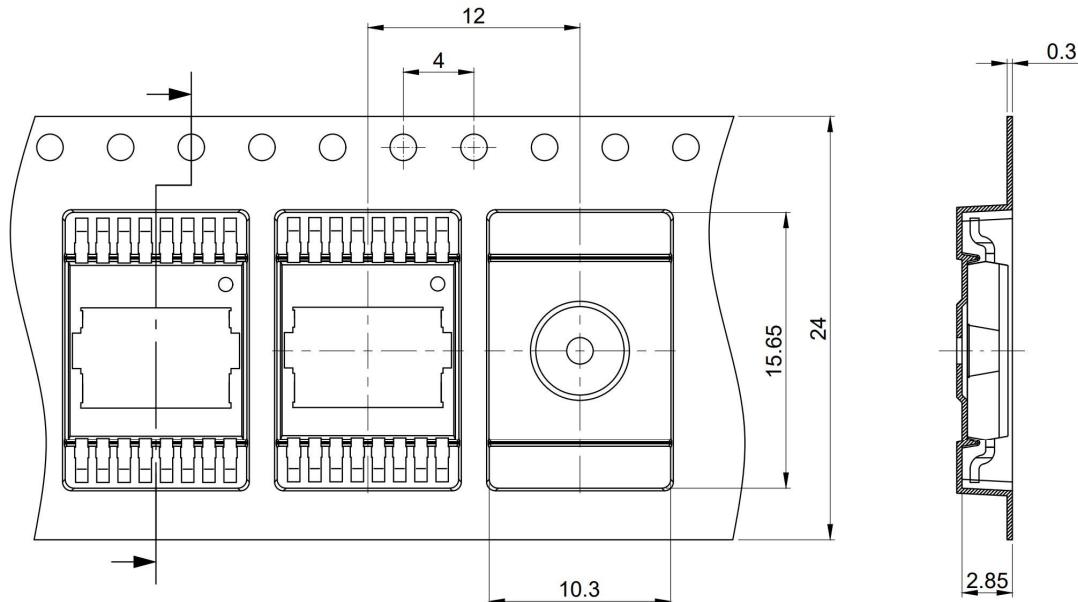
5 Package outlines



Row	Description	Example
Row 1	Device name	CGXXXXXXXX
Row 2	ASSY lot No.	XXXXXXX
Row 3	Year & Week	YXWX

Symbol	MIN	MID	MAX
A	2.200	2.275	2.350
A1	0.010	0.060	0.110
A2	0.560	0.760	0.960
b	0.600	0.725	0.850
b1	0.600	0.700	0.800
c	0.450	0.550	0.650
c1	0.450	0.525	0.600
D	10.000	10.150	10.300
D1	5.470	5.670	5.870
D2	1.800	2.000	2.200
D3	4.850	5.050	5.250
D4	5.000	5.065	5.130
D5	2.080	2.280	2.480
D6	5.170	5.370	5.570
D7	1.800	2.000	2.200
D8	0.100	0.300	0.500
D9	2.420	2.620	2.820
D10	3.850	4.050	4.250
D11	2.040	2.240	2.440
E	9.700	9.900	10.100
E1	9.260	9.460	9.660
E2	8.100	8.300	8.500
E3	4.750	4.950	5.150
E4	0.200	0.400	0.600
e	1.200 BSC.		
e1	0.600 BSC.		
e2	8.400 BSC.		
H	14.800	15.000	15.200
K	3.710	3.910	4.110
L	2.250	2.450	2.650
L1	7.300	7.500	7.700
L2	1.300	1.500	1.700
R	0.070	-	-
P	2.900	3.000	3.100
θ	4°	7°	10°

6 Tape information



All dimensions are in units mm

7 Revision history

Major changes since the last revision.

Revision	Date	Description of changes
1.0	2024-09-05	1.0 version release
1.1	2024-11-19	Update reverse gate leakage current